

<div>INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)</div>				ATTY. DOCKET NO. 4635-004		U.S. PATENT APPLICATION NO. 10/696,577	
				APPLICANT Hiroyuki NAGANO			
				FILING DATE October 30, 2003		GROUP 3713	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
mb	6,461,239	10/2002	Ozaki et al.				
mb	2001/0031658	10/2001	Sagawa et al.				
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No	
mb	2003-038696	02/2003	Japan				
mb	1 226 853	07/2002	EP				
mb	2001-309277	04/2002	Japan				
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER	DATE CONSIDERED			5/1/06			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.



INFORMATION DISCLOSURE
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APPLICATION
(PTO-1449)

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4635-004

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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
MDS	1 07-000611	01/06/1995	JAPAN			✓	
	2 07-275522	10/24/1995	JAPAN			✓	
	3 07-289697	04/25/1994	JAPAN			✓	
	4 07-295466	11/10/1995	JAPAN			✓	
	5 08-280902	10/29/1996	JAPAN			✓	
	6 10-165602	06/23/1998	JAPAN			✓	
	7 10-320647	12/04/1998	JAPAN			✓	
	8 11-057155	03/02/1999	JAPAN			✓	
	9 11-070208	03/16/1999	JAPAN			✓	
	10 11-114147	04/27/1999	JAPAN			✓	
	11 11-299907	11/02/1999	JAPAN			✓	
	12 11-313916	11/16/1999	JAPAN			✓	
	13 2000-176139	06/27/2000	JAPAN			✓	
	14 2000-342824	12/12/2000	JAPAN			✓	
	15 2001-246044	09/11/2001	JAPAN			✓	
	16 2002-085625	03/26/2002	JAPAN			✓	
	17 2002-085626	03/26/2002	JAPAN			✓	
	18 2002-085634	03/26/2002	JAPAN			✓	
	19 2002-085635	03-26-2002	JAPAN			✓	
	20 2002-166027	06/11/2002	JAPAN			✓	
	21 2002-172211	06/18/2002	JAPAN			✓	
	22 2002-177470	06/25/2002	JAPAN			✓	
	23 2002-200321	07/16/2002	JAPAN			✓	
	24 2002-263326	09/17/2002	JAPAN			✓	
	25 2002-306804	10/22/2002	JAPAN			✓	
	26 2002-334162	11/22/2002	JAPAN			✓	
	27 2003-000818	01/07/2003	JAPAN			✓	
	28 2003-024573	01/28/2003	JAPAN			✓	
	29 2003-03896	02/12/2003	JAPAN			✓	
	30 2003-053027	02/25/2003	JAPAN			✓	
	31 2003-062327	03/04/2003	JAPAN			✓	
	32 2003-108465	04/11/2003	JAPAN			✓	
	33 2003-190397	07/08/2003	JAPAN			✓	
MDS	34 2003-242230	08/29/2003	JAPAN			✓	
	35 2003-290473	10/14/2003	JAPAN			✓	
MDS	36 2003-325912	11/18/2003	JAPAN			✓	

EXAMINER *[Signature]*

DATE CONSIDERED *5/1/06*

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